Applicant(s)/Patent Under Application/Control No. Reexamination 10/656,512 AWAKURA ET AL. Notic of R ferenc s Cited Examiner Art Unit Page 1 of 1 Tuan T Dinh 2827 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-5,835,313 Α 11-1998 Sato et al. 360/317 В US-5,959,813 09-1999 Watanabe et al. 360/126 US-6,134,079 C 10-2000 Koshikawa, Takao 360/126 US-6,154,349 11-2000 Kanai et al. D 360/324.12 E US-6,469,868 10-2002 Yamamoto et al. 360/126 US-F US-G US-Н US-١ US-J Κ UŞ-US-US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 10105961 A Ν 04-1998 Japan SEO, YUZO G11B 05/82 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

W

Х